Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.	
	A1							
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## **Foreign Patent Documents**

Exam. Init.	Ref. Document Des. Number		Date	Country	Class	Sub Class	Translation Yes/No	
	BI							
	B2							
	В3							
	B4							
	B5							

## Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.					
	Cl	Horiguchi, Usuki, Goto, Futatsugi, Sugii and Yokoyama: "Retention Time Enhancement in Direct Tunneling Memory (DTM) Utilizing Floating Gate Depletion by Diffusion Stopper," pgs. 458-458.3				

Examiner:	Ch	myaMh	-	DATE CONSIDERED:	1/21	105
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